

**REMARKS**

The present application includes claims 1-19 and 21. Claims 10-19 were rejected by the Examiner. Claims 1-9 and 21 have been allowed by the Examiner. By this response, claims 10, 11 and 18 have been amended.

In accordance with the Examiner's statement in the Office Action of September 9, 2005, claims 11 and 18 have been rewritten in independent form including all of the limitations of their base claim 10. The Applicant respectfully requests allowance of independent claims 11 and 18, as well as dependent claim 19, which depends from claim 18. Additionally, claims 10, 11 and 18 have been amended to clarify that the electron beam produces energy to irradiate the array of detector elements, rather than directly irradiating the detector elements with the electron beam.

The drawings have been objected to under 37 CFR 1.83(a) because they fail to show the multipin phantom (775) in Fig. 7. By this response, the Applicant submits corrected drawings to include the omitted reference numeral 775 in Fig. 7. The Applicant requests that the Examiner's objection be withdrawn.

Claims 10-19 were rejected under 35 U.S.C. § 112, first paragraph, as being not enabled by the specification without the use of a multipin phantom. However, claim 18 does include mention of a multipin phantom. Claim 18 was previously rewritten in independent form, and the Applicant respectfully submits that claim 18 and its dependent claim 19 should be allowable as the Examiner had previously indicated an independent claim 11, which also mentions the use of a multipin phantom, would be allowable in his office action of September 9, 2005.

Additionally, the Examiner states that the specification does not enable any person skilled in the art to which it pertains, or to which it is most nearly connected, to practice the invention commensurate in scope with claims 10-19. The Examiner states that the invention requires imaging a multipin phantom and that the array of detectors is irradiated by an x-ray beam and not electrons. The Applicant respectfully disagrees with these characterizations.

Figures 7 and 8 of the present application illustrate an electron beam tuning system 700 formed in accordance with an embodiment of the present invention and a flow diagram 800 for a method for adjusting an electron beam used in accordance with an embodiment of the present invention, respectively. As clarified in the amendment, the specification clearly envisions application to an electron beam which results in production of an energy beam, such as an x-ray beam, which then irradiates the detector elements.

Furthermore, the disclosure in the application with respect to Figures 7 and 8, from paragraph [56] to paragraph [68], illustrates a scope of operation including a multipin phantom and beyond. Figure 7 uses a multipin phantom purely as an example but does not rely solely on the use of a multipin phantom to correct a radius of a motion pattern of an electron beam based on variation of the radius from a desired radius over time. Additionally, the discussion of the system 700 and Figure 7 does not rely solely on the use of a multipin phantom to adjusting an angle of the motion pattern of the electron beam based on variation of position of the motion pattern from a desired position over time. (See, e.g., paras. [58]-[62]). In addition, Figure 8 describes an embodiment of a motion for adjusting an electron beam without mention of a multipin phantom at all. (See, paras. [63]-[67]). Therefore, the Applicant submits that claim 10 and dependent claims 12-17 are in condition for allowance. The Examiner had previously indicated that claims 10 and 12-17 were allowable, and action to that affect is respectfully

requested. Additionally, the Examiner had previously indicated that an independent claim 11 was allowable, and claim 18 has similarly been rewritten in independent form. Thus, the Applicant thanks the Examiner for his allowance of claims 1-9 and 21 and requests allowance of the remaining claims 10-19 based at least on the discussion above.

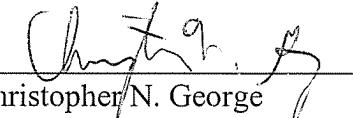
**CONCLUSION**

The Applicants submit that the present application is in condition for allowance. If the Examiner has any questions or the Applicants can be of any assistance, the Examiner is invited and encouraged to contact the Applicants at the number below. In particular, should the Examiner have any questions concerning the definiteness of the claims in pointing out and distinctly claiming the subject matter which the Applicants regard as the invention, the Examiner is invited and encouraged to contact the Applicants at the number below.

The Commissioner is authorized to charge any additional fees or credit overpayment to the Deposit Account of GTC, Account No. 070845.

Respectfully submitted,

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